# MSKSEMI 美森科













**ESD** 

TVS

TSS

MOV

GDT

PIFD

**AO3402** 

Product specification





## **Features**

- 30V, 4.0 A, RDS(ON) =  $47m\Omega$ @VGS = 4.5V
- Improved dv/dt capability
- Fast switching
- Green Device

# **Applications**

- Notebook
- Load Switch
- LED applications

BVDSS	RDSON	ID
30V	47mΩ	4.0A

## **Reference News**

PACKAGE OUTLINE	PIN Configuration	Marking
SOT-23-3L	Go	<b>A2</b> ** ĕ

# Absolute Maximum Ratings Tc=25℃ unless otherwise noted

Symbol	Parameter	Rating	Units
V <sub>D</sub> s	Drain-Source Voltage	30	V
Vgs	Gate-Source Voltage	±12	V
<b>l</b> b	Drain Current - Continuous (Tc=25°C)	4.0	А
	Drain Current - Continuous (Tc=100°C)	3.0	Α
Ірм	Drain Current - Pulsed¹	16	А
<b>D</b>	Power Dissipation (Tc=25°C)	1.4	W
PD	Power Dissipation - Derate above 25°C	0.012	W/°C
Тѕтс	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C

## **Thermal Characteristics**

Symbol	Parameter	Тур.	Max.	Unit
Reja	Thermal Resistance Junction to ambient		80	°C/W



## Electrical Characteristics (TJ=25 ℃, unless otherwise noted)

#### **Off Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	Vgs=0V , Ip=250uA	30			V
△BV <sub>DSS</sub> /△T <sub>J</sub>	BVDSS Temperature Coefficient	Reference to 25°C , I□=1mA		0.06		V/°C
L	Drain-Source Leakage Current	Vbs=30V , Vgs=0V , TJ=25℃			1	uA
IDSS	Diam-Source Leakage Current	V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , T <sub>J</sub> =125℃			10	uA
Igss	Gate-Source Leakage Current	Vgs=±12V, Vps=0V			±100	nA

#### On Characteristics

Rds(on)	Static Drain-Source On-Resistance	V <sub>G</sub> s=4.5V , I <sub>D</sub> =4A		47	60	mΩ
TADS(ON)	Statio Brain Godice on Resistance	Vgs=2.5V , ID=3A		60	85	11177
V <sub>GS(th)</sub>	Gate Threshold Voltage	-Vgs=Vds , Id =250uA	0.5	0.9	1.4	V
$\triangle V$ GS(th)	V <sub>GS(th)</sub> Temperature Coefficient	7 VG3- VD3 , ID -230UA		-3		mV/℃
gfs	Forward Transconductance	V <sub>DS</sub> =10V , I <sub>S</sub> =3A		7		S

**Dynamic and switching Characteristics** 

Dynamic an	a switching offaracteristics				
Qg	Total Gate Charge <sup>2,3</sup>		 8.4		
Qgs	Gate-Source Charge <sup>2, 3</sup>	V <sub>DS</sub> =10V , V <sub>GS</sub> =4.5V , I <sub>D</sub> =3A	 1		nC
Qgd	Gate-Drain Charge <sup>2, 3</sup>		 2.2		
Td(on)	Turn-On Delay Time <sup>2,3</sup>		 4.5		
Tr	Rise Time <sup>2 , 3</sup>	V <sub>DD</sub> =10V , V <sub>GS</sub> =4.5V ,	 13		20
T <sub>d(off)</sub>	Turn-Off Delay Time <sup>2, 3</sup>	R <sub>G</sub> =25Ω l <sub>D</sub> =1A	 27		nS
Tf	Fall Time <sup>2, 3</sup>		 8.3		
Ciss	Input Capacitance		 695	-	
Coss	Output Capacitance	V <sub>DS</sub> =10V , V <sub>GS</sub> =0V , F=1MHz	 45		pF
Crss	Reverse Transfer Capacitance		 36	-	
Rg	Gate resistance	V <sub>G</sub> s=0V, V <sub>D</sub> s=0V, F=1MHz	 1.5		Ω

**Drain-Source Diode Characteristics and Maximum Ratings** 

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current	-		4.0	Α
lsм	Pulsed Source Current	VG-VD-OV , I OIGE Gairent	I	I	8.0	Α
VsD	Diode Forward Voltage	V <sub>G</sub> s=0V , I <sub>S</sub> =1A , T <sub>J</sub> =25℃	-	-	1.2	V

#### Note:

- 1. Repetitive Rating : Pulsed width limited by maximum junction temperature.
- 2. The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%.
- 3. Essentially independent of operating temperature.

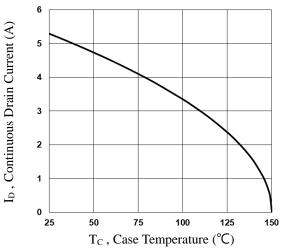


Fig.1 Continuous Drain Current vs. Tc

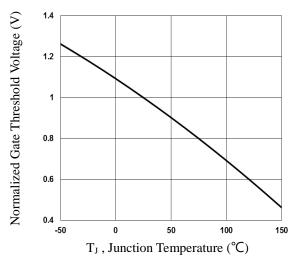


Fig.3 Normalized  $V_{th}$  vs.  $T_J$ 

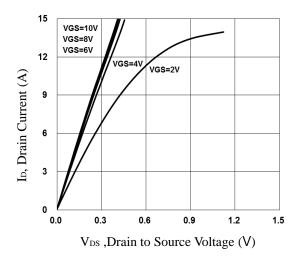


Fig.5 Typical Output Characteristics

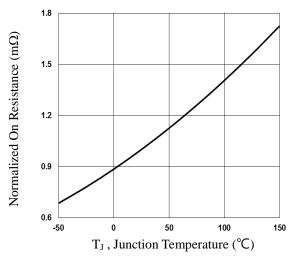


Fig.2 Normalized RDSON vs. T<sub>J</sub>

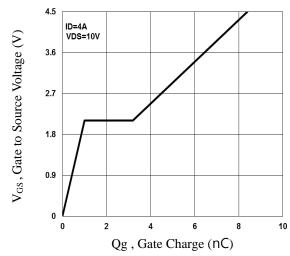


Fig.4 Gate Charge Waveform

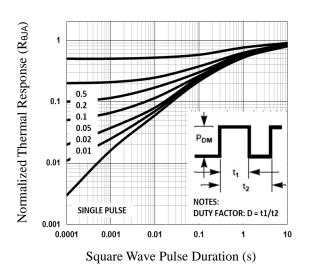


Fig.6 Normalized Transient Impedance

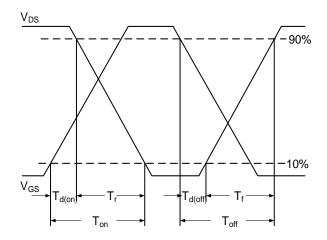


Fig.8 Switching Time Waveform

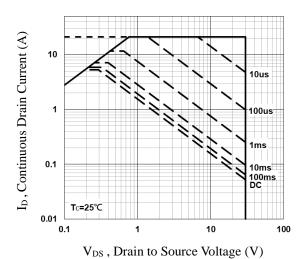


Fig.7 Maximum Safe Operation Area

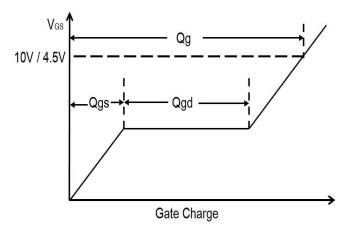
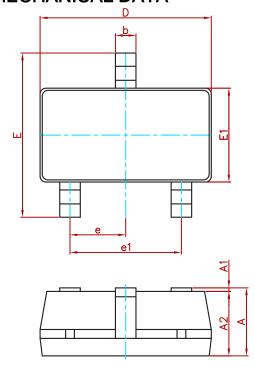
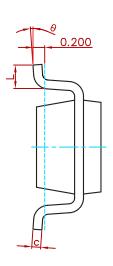


Fig.9 Gate Charge Waveform



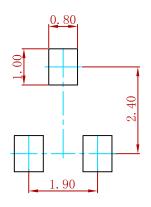
# PACKAGE MECHANICAL DATA





Symbol	Dimensions II	Dimensions In Millimeters		s In Inches
Symbol	Min.	Max.	Min.	Max.
Α	1.050	1.250	0.041	0.049
A1	0.000	0.100	0.000	0.004
A2	1.050	1.150	0.041	0.045
b	0.300	0.500	0.012	0.020
С	0.100	0.200	0.004	0.008
D	2.820	3.020	0.111	0.119
E1	1.500	1.700	0.059	0.067
E	2.650	2.950	0.104	0.116
е	0.950(	BSC)	0.037	(BSC)
e1	1.800	2.000	0.071	0.079
L	0.300	0.600	0.012	0.024
А	0°	8°	0°	8°

# **Suugested Pad Layout**



#### Note:

- 1.Controlling dimension:in millimeters.
- 2.General tolerance:± 0.05mm.
- 3. The pad layout is for reference purposes only.

## **REELSPECIFICATION**

P/N	PKG	QTY
AO3402	SOT-23-3L	3000



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